

Registration

To register for PRORA 2017, please fill in the online form at iap-adlershof.com

The registration of talks and posters is kindly requested until 25 August 2017. Please submit title, author(s) and an abstract.

The early bird registration fee is available until 25 August 2017. Especially students are warmly welcome to participate and to present a poster or to give a talk.

Accommodation can be reserved at reduced rates until 2 November 2017.

Framework event

The Satellite Meeting of "Berlin Laboratory for innovative X-ray Technologies (BLiX)" and the founder meeting will be held on 29 November 2017 at TU Berlin.

Organisation

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Organisers

IAP Institut für angewandte Photonik e.V., Berlin
IfG – Institute for Scientific Instruments GmbH, Berlin
Bundesanstalt für Materialforschung und -prüfung, Berlin
Bruker Nano GmbH, Berlin
Helmut Fischer Stiftung, Stuttgart
Optec-Berlin-Brandenburg e.V.
Physikalisch-Technische Bundesanstalt, Braunschweig und Berlin
Arbeitskreis Prozessanalytik
SPECTRO Analytical Instruments GmbH, Kleve
Technische Universität Berlin
WISTA-MANAGEMENT GMBH
Berlin Partner für Wirtschaft und Technologie GmbH

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Programme committee

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F. Emmerling, BAM, Berlin
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A. Kharchenko, PANalytical, Almelo, Niederlande
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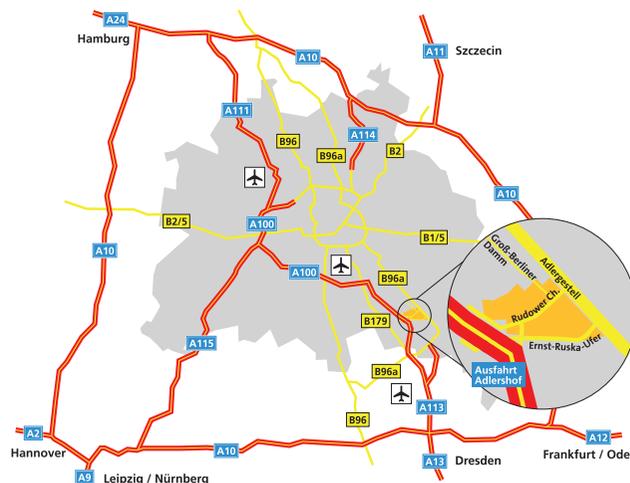
Directions also at www.adlershof.de

Fees

Attendance fee	Early bird until 25 August 2017	Regular
Regular attendee	150,00 €	200,00 €
Students	20,00 €	55,00 €

Exhibition space	100,00 €/m ²	150,00 €/m ²
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Acomodation	Dorint Adlershof	airporthotel Adlershof
Single room	90,00 €/room/night	64,00 €/room/night
Double room	108,00 €/room/night	79,00 €/room/night
Breakfast	included	13,00 €/person/night



Conference announcement

Symposium Prozessnahe Röntgenanalytik

30 November – 1 December 2017

WISTA – Wissenschafts- und Technologiepark Adlershof
BAM Bundesanstalt für Materialforschung und -prüfung
Haus 8.05
Richard-Willstätter-Straße 11
12489 Berlin

Analytics 5.0 for Industry 4.0

The 9th conference on X-ray analytics for industrial processes PRORA will take place on 30 November and 1 December 2017.

Industry 4.0 is on everyone's lips and requires modern analytics 5.0 for monitoring and controlling the processes. Users, developers and manufacturers who are working in the field of process related X-ray analytics and its combination with optical measuring methods, are invited to participate in the conference and trade exhibition PRORA. Further interested parties and especially students are welcome.

At this year's conference the key focus will be on a broad spectrum of process-analytical procedures which illustrate the networking of sensor systems with process control and regulating systems. The recycling industry for the recovery of scarce materials is a very important field of application. Process-analytical methods ensuring the economical use of energy and raw materials in the production of high-quality items in various industries like electronics industry, chemical industry, automotive industry are also outstanding topics.

Know-how exchange on process-related X-ray analytics already established in industry, advances in research and development, and innovative strategies will be subject of discussion. This involves methods as well as individual components, devices, and systems.

Along with the conference there will be a device exhibition. Exhibitors will have the opportunity to present their product portfolio. The presentations will take place before the poster session on 30 November 2017. The time per speaker is limited to five minutes. The set-up of the exhibition will start on 29 November 2017 from 1.00 pm.

The venue is the Berlin-Adlershof Scientific and Technology Park in a new setting at the Federal Institute for Materials Research and Testing.



Topics

1 Methodic challenges

- ▶ Comparison and coupling of different analytical methods using X-rays, VUV, IR or Terahertz Radiation for process control
- ▶ New methods for the application of X-ray analytics in industrial environments
- ▶ Development of measurement software for quality and process control
- ▶ Reliability and safety of data in a digital environment

2 Industrial applications

- ▶ Process analytics for recycling
- ▶ Linkage of objects, probes and automation for process control, examples from machinery, electronic, automotive or chemical industry
- ▶ Combination of X-ray and optical methods in an industrial environment
- ▶ Challenges for measuring devices and equipment for field analyses

3 New X-ray methods

- ▶ X-ray micro analysis of light elements
- ▶ Time resolved X-ray techniques
- ▶ X-ray microscopy and absorption spectroscopy with lab devices
- ▶ Speciation by X-ray

4 Newly developed components for process analytical devices

- ▶ Combined X-ray and VIS components
- ▶ Improvements concerning capillary optics
- ▶ X-ray sources for process analytics
- ▶ X-ray detection devices for industrial environments